

Notice of References Cited

Application/Control No.

10/055,421

Applicant(s)/Patent Under

Reexamination

DICKEN ET AL.

Examiner

Jacob Y Choi

Art Unit

2875

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4164010	08-1979	Finch	362/417
	B	US-3463914	07-1967	T. Lutter	---
	C	US-2330935	10-1943	D. H. Tuck	---
	D	US-6019476	02-2000	Kirschner	362/2
	E	US-4293892	10-1981	Plummer	362/17
	F	US-5934779	08-1999	Leidig	362/17
	G	US-6400905	06-2002	Tenmyo	396/175
	H	US-5961196	10-1999	Long et al.	362/17
	I	US-5384658	01-1995	Ohtake et al.	359/707
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.